# Notice of References Cited Application/Control No. 10/588,779 Applicant(s)/Patent Under Reexamination YAMAGUCHI ET AL. Examiner STEVEN M. CERNOCH 3752 Applicant(s)/Patent Under Reexamination YAMAGUCHI ET AL. Page 1 of 3

# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2,525,347 A	10-1950	SAMUEL GILMAN	95/71
*	В	US-3,887,928 A	06-1975	Ohno et al.	347/55
*	С	US-4,120,015 A	10-1978	Haller, Jack R.	361/227
*	D	US-4,248,386 A	02-1981	Morle, Charles W.	239/707
*	Е	US-4,380,786 A	04-1983	Kelly, Arnold J.	361/228
*	F	US-4,962,885 A	10-1990	Coffee, Ronald A.	239/3
*	G	US-5,163,625 A	11-1992	Takayama et al.	239/703
*	Ι	US-5,184,778 A	02-1993	Noakes, Timothy J.	239/691
*	ı	US-5,221,050 A	06-1993	Jeffries et al.	239/708
*	٦	US-5,218,290 A	06-1993	Beckert et al.	324/115
*	K	US-5,337,963 A	08-1994	Noakes, Timothy J.	239/690
*	L	US-5,512,228 A	04-1996	Adams et al.	264/152
*	М	US-5,591,412 A	01-1997	Jones et al.	422/171

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. 10/588,779 Applicant(s)/Patent Under Reexamination YAMAGUCHI ET AL. Examiner STEVEN M. CERNOCH 3752 Applicant(s)/Patent Under Reexamination YAMAGUCHI ET AL.

# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,704,554 A	01-1998	Cooper et al.	239/690.1
*	В	US-5,725,161 A	03-1998	Hartle, Ronald J.	239/690
*	С	US-5,788,468 A	08-1998	Dewa et al.	417/415
*	D	US-5,813,614 A	09-1998	Coffee, Ronald Alan	239/690
*	Е	US-5,927,618 A	07-1999	Jefferies et al.	239/690.1
*	F	US-6,050,498 A	04-2000	Minoura et al.	239/112
*	G	US-6,311,903 B1	11-2001	Gaw et al.	239/690
*	Н	US-6,318,647 B1	11-2001	Gaw et al.	239/690
*	I	US-2002/0100815 A1	08-2002	Doebler et al.	239/67
*	J	US-6,460,781 B1	10-2002	Garcia et al.	239/327
*	К	US-6,595,208 B1	07-2003	Coffee et al.	128/203.12
*	L	US-2004/0057720 A1	03-2004	Westerweck et al.	396/448
*	М	US-6,708,908 B2	03-2004	Heldt et al.	239/700

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. 10/588,779 Examiner STEVEN M. CERNOCH Applicant(s)/Patent Under Reexamination YAMAGUCHI ET AL. Art Unit Page 3 of 3

# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,744,046 B2	06-2004	Valaskovic et al.	250/288
*	В	US-6,911,132 B2	06-2005	Pamula et al.	204/600
*	O	US-2005/0207914 A1	09-2005	Tupy, Matthias	417/410.1
*	D	US-2005/0196301 A1	09-2005	Iwasaki, Mitsutaka	417/410.4
*	Е	US-7,091,430 B1	08-2006	Haizima et al.	200/6A
*	F	US-2007/0159015 A1	07-2007	Lin et al.	310/071
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	S					
	Т					

### **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	С	
	>	
	w	
	x	

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.